

Search Notes

Application/Control No.

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Examiner

Patricia Leith

Applicant(s)/Patent under
Reexamination

LEE, YUAN Y.

Art Unit

1655

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE updated	7/8/2007	PL
Inventor name search updated EAST/PALM	7/8/2007	PL